XDS Rapid Content™ Analyser

- with ISIscan™ software



The XDS Rapid ContentTM with ISIscanTM software provides rapid non-destructive analysis of solid and semi-solid samples.

Features and benefits

- Rapid non-destructive analysis of solid, viscous and liquid samples for routine process control and research laboratory applications
- Superior analytical performance provides high quality results in less than 60 seconds
- Instrument standardisation reduces calibration costs by allowing the same calibration to be used on different instruments
- 400 2500 nm scanning range with sensitive outlier detection minimises the number of samples needed to get a robust calibration model
- Flexible sample presentation in standard XDS sample cups or in disposable plastic bags, glass vials or beakers
- A safe and environmentally-friendly solution that does not involve sample preparation, reagents, hazardous chemicals or chemical waste
- Meets NEMA12/IP55 requirements make the analysis where you need the results
- Use PLS, ANN or LOCAL calibration models

Technical exellence

Offering outstanding performance and patented scanning technology that provides excellent

transferability, the XDS Rapid ContentTM Analyser represents the top end of the FOSS NIR product portfolio. Technical excellence ensures simplicity of use, efficient operations and the capacity to handle a wide range of sample types.

The advanced features provided by XDS NIR technology together with the well known WinISITM calibration development software minimise implementation time for the instrument and ensure seamless calibration model transferability between instruments. Flexibility of sample presentation allows simple and fast measurements with results delivered in less than a minute. For routine operations, ISIscanTM software provides a user-friendly interface supporting the latest calibration technologies with advanced data exchange (LIMS) and reporting capabilities. The broad scanning range provides new opportunities to measure diverse parameters.

For routine analysis or research laboratory application

XDS Rapid Content analyser is ideal for agricultural research laboratory applications and routine analysis.



For research laboratory applications, the broad scanning range (VIS and NIR) and the flexible sample presentation provides a highly versatile analysis platform that is both accurate and fast.

For routine analysis, the instrument can be used for analysis of raw materials, for process control and for analysis of final products. Relevant features include easy-to-make robust calibrations, transferable calibration models between instruments, full spectra outlier detection for secure results, NIST traceable performance test and versatile sample presentation.

System description:

XDS NIR Rapid ContentTM Analyser includes:

1 pcs XDS laboratory monochromator

1 pcs XDS Rapid ContentTM module with solid module

1 pcs XDS RCM iris

1 pcs NIRStandards™ certified standard

1 pcs ISIscanTM

1 pcs XDS accessory kit

1 pcs XDS Rapid ContentTM Analyser installation and operation manual

Accessories:

Mini sample cup set
Coarse granular sample cell
Liquid sample kit for RCA
WinISITM III calibration development software
NIRStandard certified reflectance standard

Technical data:

Data acquisition rate:

Wavelength range: 400 - 2500 nmOperating temperature: $5 - 35^{\circ}\text{C} (40 - 95^{\circ}\text{F})$ Operating humidity: 10 - 90% relative Dual detector system: Silicon (400-1100nm), Lead Sulphide (1100-2500nm)

> 2 scan/sec 2 nm

Spectral resolution: 2 nm Wavelength accuracy: <0.05 nm

Dimensions (w x d x h): 457 x 572 x 387 mm

Weight: 31.25 kg

US Patent no. 4,997,280, SPECTROPHOTOMETRIC INSTRUMENT WITH RAPID SCANNING DISTORTION CORRECTION

US Patent no. 6,031,608, SPECTROPHOTOMETRIC INSTRUMENT WITH RAPID OFFSET GRATING TO IMPROVE FOCUS

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